

# EECE 598, Homework 05

Try to solve the problems by yourselves. Compare with your solutions after you are done. Exams will be similar formats as these.

1. **Problem 6-1.**
2. **Problem 6-3.**
3. **Problem 6-6.**

No submission is required. The solutions to select problems will be uploaded a week later.

**6.1** Consider the absorption coefficient of silicon as a function of wavelength, as shown in Fig. 6.18. Ignoring reflections at the photodiode surface, plot the following two parameters over the wavelength range 600–1000 nm:

- (a) The quantum efficiency for depletion layer widths of 1, 5, 10, 20, and 50  $\mu\text{m}$ .
- (b) The responsivity for a silicon *pin* photodiode having a 20- $\mu\text{m}$  thick depletion layer.

**6.3** If the absorption coefficient of silicon is  $0.05 \mu\text{m}^{-1}$  at 860 nm, find the penetration depth at which  $P(x)/P_{in} = 1/e = 0.368$ .

**6.6** An InGaAs *pin* photodiode has the following parameters at 1550 nm:  $I_D = 1.0 \text{ nA}$ ,  $\eta = 0.95$ ,  $R_L = 500 \Omega$ , and the surface leakage current is negligible. The incident optical power is 500 nW (−33 dBm) and the receiver bandwidth is 150 MHz. Compare the noise currents given by Eqs. (6.14), (6.15), and (6.16).